

## 100V N-Channel Enhancement Mode MOSFET

### Description

The AP15N10BD uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = 100V$   $I_D = 15A$

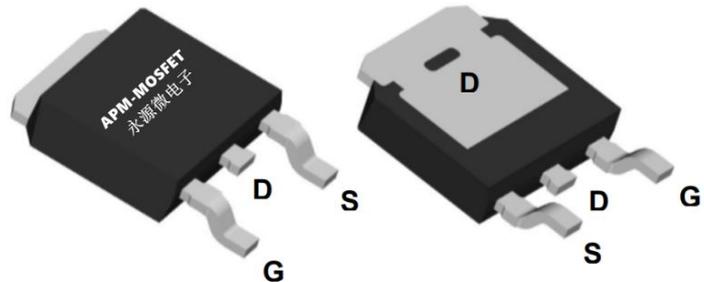
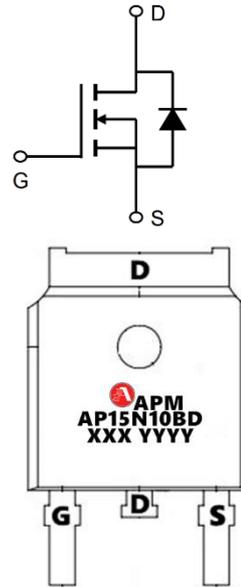
$R_{DS(ON)} < 100m\Omega @ V_{GS}=10V$  (Type: 85m $\Omega$ )

### Application

Automotive lighting

Load switch

Uninterruptible power supply



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP15N10BD	TO-252-3L	AP15N10BD XXX YYYY	2500

### Absolute Maximum Ratings (TC=25°C unless otherwise noted)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	100	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D @ T_C=25^\circ C$	Drain Current, $V_{GS} @ 10V$	15	A
$I_D @ T_C=100^\circ C$	Drain Current, $V_{GS} @ 10V$	6.5	A
IDM	Pulsed Drain Current <sup>1</sup>	25	A
$P_D @ T_C=25^\circ C$	Total Power Dissipation	44	W
TSTG	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C
$R_{\theta JA}$	Maximum Thermal Resistance, Junction-ambient	62.5	°C/W
$R_{\theta JC}$	Maximum Thermal Resistance, Junction-case	6	°C/W



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### Electrical Characteristics@T<sub>j</sub>=25°C(unless otherwise specified)

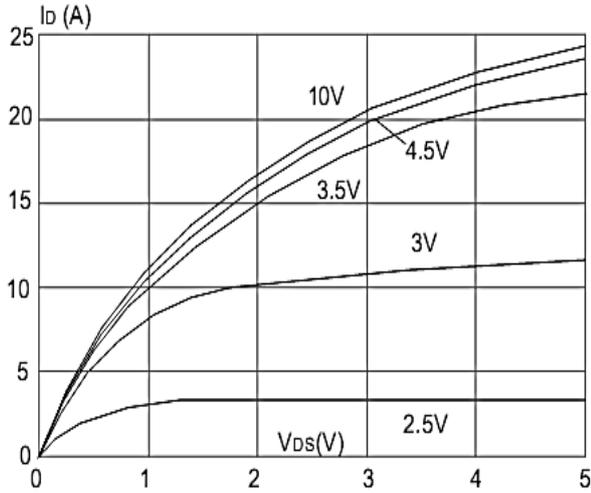
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	VGS=0V, ID=250μA	100	-	-	V
IDSS	Zero Gate Voltage Drain Current	VDS=100V, VGS=0V,	-	-	1.0	μA
IGSS	Gate to Body Leakage Current	VDS=0V, VGS=±20V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	VDS=VGS, ID=250μA	1.0	1.5	2.5	V
RDS(on)	Static Drain-Source on-Resistancenote3	VGS=10V, ID=5A	-	85	100	mΩ
		VGS=4.5V, ID=3A	-	96	125	mΩ
Ciss	Input Capacitance	VDS=50V, VGS=0V, f=1.0MHz	-	547	-	pF
Coss	Output Capacitance		-	30	-	pF
Crss	Reverse Transfer Capacitance		-	8	-	pF
Qg	Total Gate Charge	VDS=50V, ID=2A, VGS=10V	-	20	-	nC
Qgs	Gate-Source Charge		-	2.8	-	nC
Qgd	Gate-Drain("Miller") Charge		-	4	-	nC
td(on)	Turn-on Delay Time	VDS=50V, ID=3A, RG=1.8Ω, VGS=10V	-	6	-	ns
tr	Turn-on Rise Time		-	7	-	ns
td(off)	Turn-off Delay Time		-	21	-	ns
tf	Turn-off Fall Time		-	3	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	15	A
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	40	A
VSD	Drain to Source Diode Forward Voltage	VGS=0V, IS=10A	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	IF=10A, dI/dt=100A/μs	-	22	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	29	-	nC

**Note :**

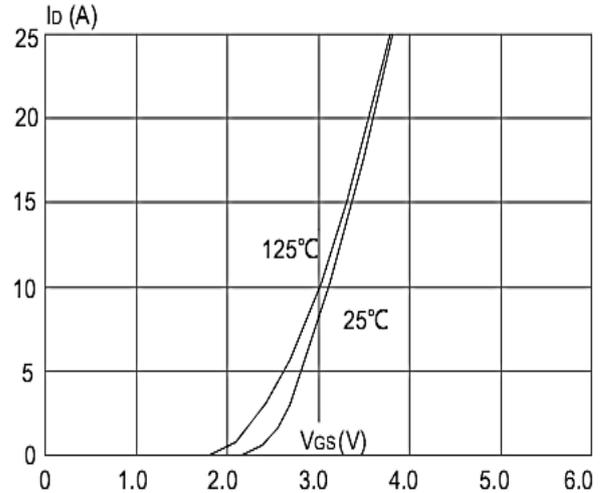
- 1、 The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
- 3、 The power dissipation is limited by 150°C junction temperature
- 4、 The data is theoretically the same as I D and I DM , in real applications , should be limited by total power dissipation.

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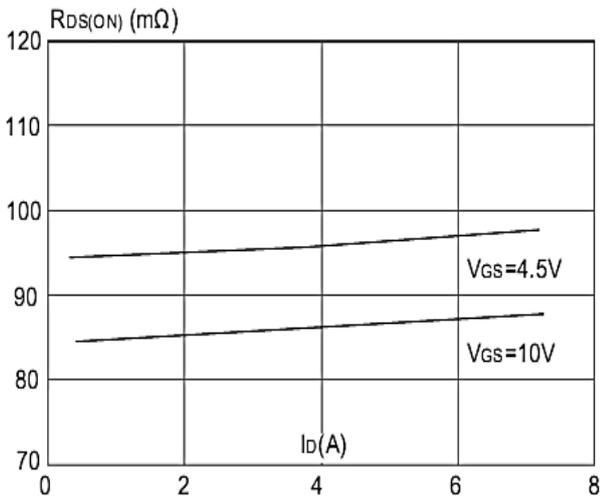
**Typical Characteristics**



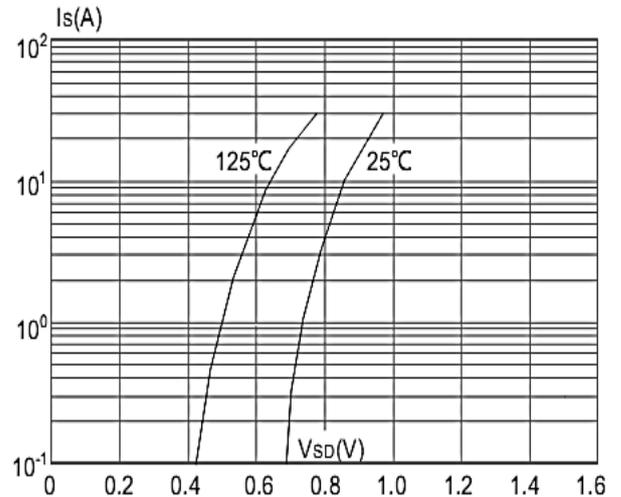
**Figure 1: Output Characteristics**



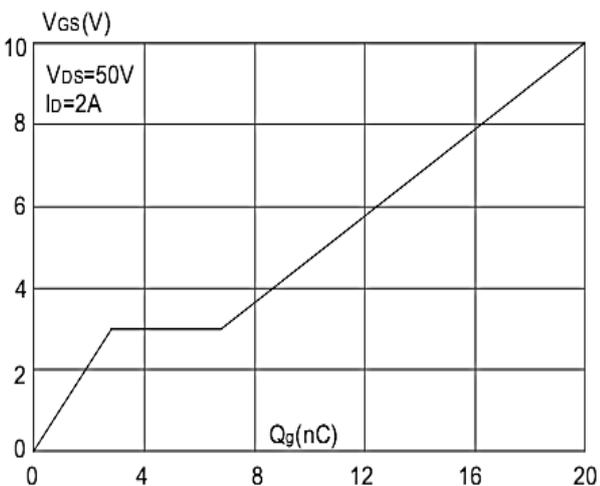
**Figure 2: Typical Transfer Characteristics**



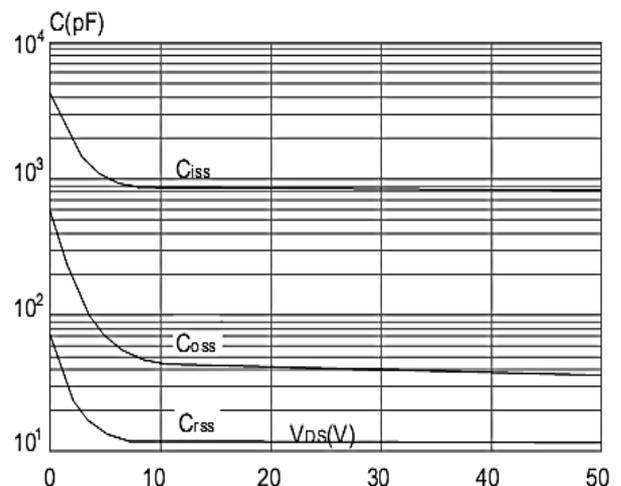
**Figure 3: On-resistance vs. Drain Current**



**Figure 4: Body Diode Characteristics**



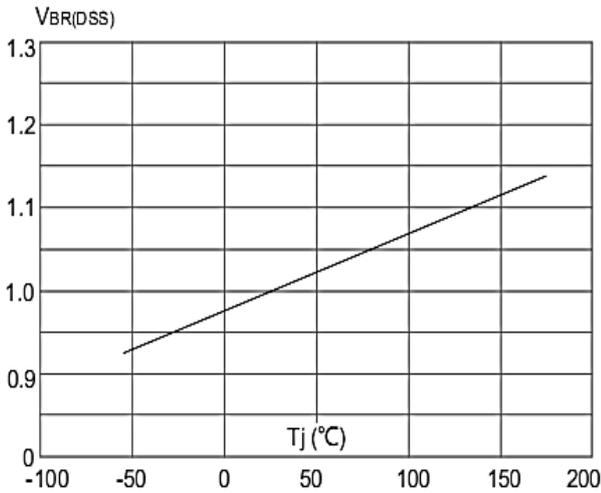
**Figure 5: Gate Charge Characteristics**



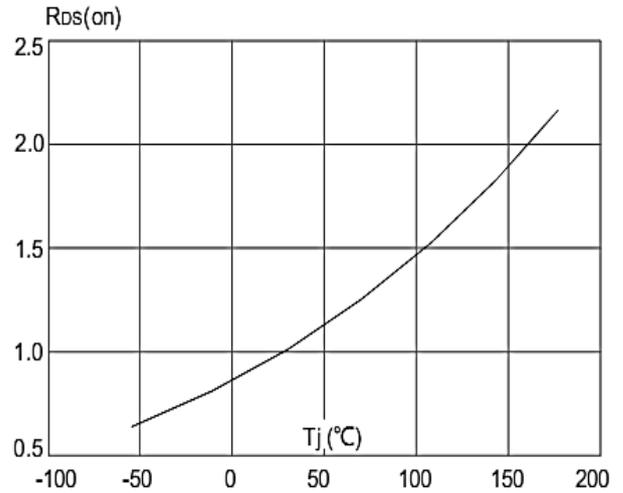
**Figure 6: Capacitance Characteristics**



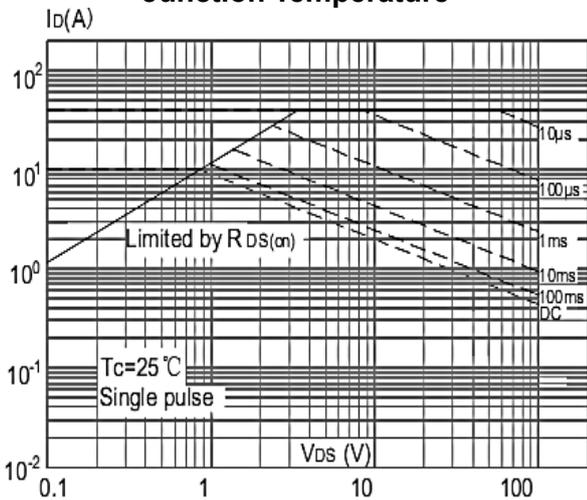
**100V N-Channel Enhancement Mode MOSFET**



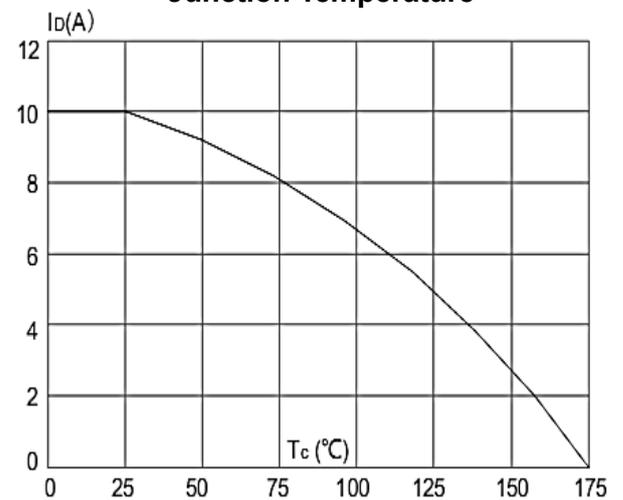
**Figure 7: Normalized Breakdown Voltage vs. Junction Temperature**



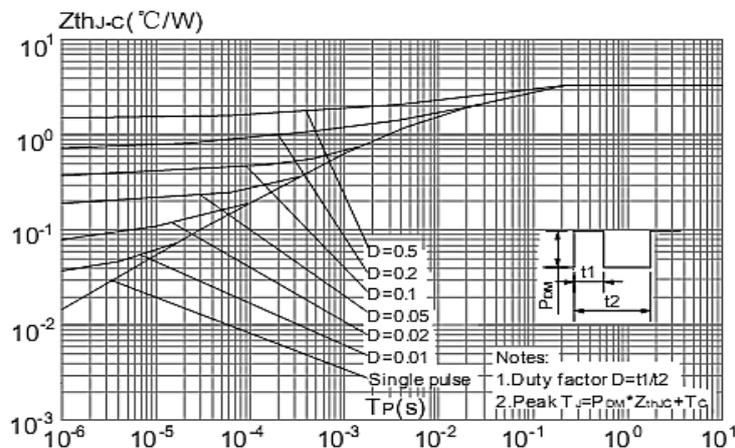
**Figure 8: Normalized on Resistance vs. Junction Temperature**



**Figure 9: Maximum Safe Operating Area**



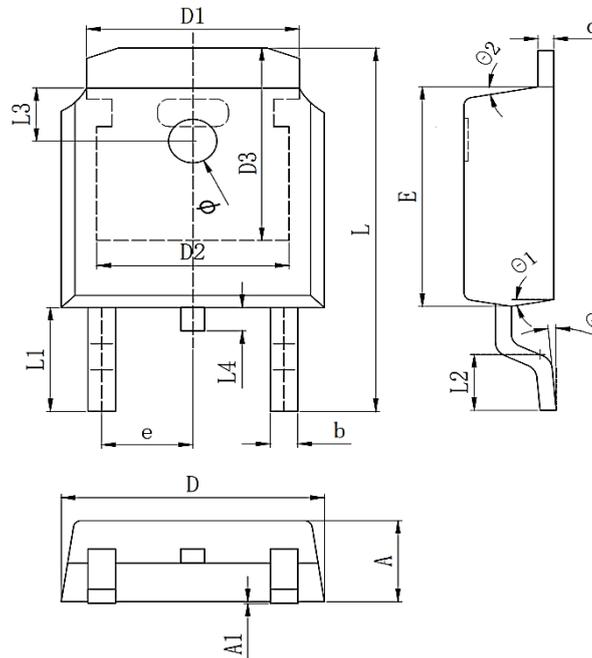
**Figure 10: Maximum Continuous Drain Current vs. Case Temperature**



**Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case**

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## Package Mechanical Data-TO-252-3L



Symbol	Dim in mm		
	Min	Typ	Max
A	2.1	2.3	2.5
A1	0	0.064	0.128
b	0.64	0.75	0.86
c	0.45	0.52	0.6
D	6.4	6.6	6.8
D1	5.33REF		
D2	4.83REF		
D3	5.25REF		
E	5.9	6.1	6.3
e	2.286TYP		
L	9.8	10.1	10.4
L1	2.888REF		
L2	1.4	1.5	1.7
L3	1.65REF		
L4	0.6	0.8	1
$\phi$	1.1	1.2	1.3
$\theta$	0°		10°
$\theta_1$	5°		10°
$\theta_2$	5°		10°

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Edition	Date	Change
REV1.0	2024/1/31	Initial release

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